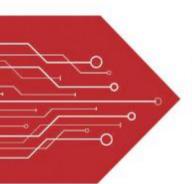
# MSKSEMI















**ESD** 

TVS

TSS

MOV

**GDT** 

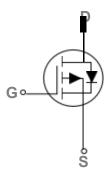
**PLED** 

Product data sheet



## SOT-323 Pin Configuration





#### **Features**

- -20V, 1.5A, RDS(ON) =  $90m\Omega$ @ VGS = -4.5V
- Improved dv/dt capability
- Fast switching
- Green Device Available

## **Applications**

- Notebook
- Load Switch
- Battery Protection
- Hand-held Instruments

BVDSS	RDSON	ID
-20V	$90 \text{m}\Omega$	-1.5A

#### Absolute Maximum Ratings Tc=25 $\ensuremath{\mathtt{c}}$ unless otherwise noted

Symbol	Parameter	Rating	Units
V <sub>DS</sub>	Drain- Source Voltage	-20	V
Vgs	Gate- Sour ce Voltage	± 12	V
	Drain Current – Continuous (Tc=25°C)	- 1.5	Α
lo	Drain Current – Continuous (Tc=100°C)	-0.95	Α
Ідм	Drain Current – Pulsed <sup>1</sup>	-6	Α
D	Power Dissipation (Tc=25℃)	312	m₩
P <sub>D</sub>	Power Dissipation – Derate above 25°C	2.5	mW/°C
Тѕтс	Storage Temperature Range	-55 to 150	℃
TJ	Operating Junction Temperature Range	-55 to 150	°C

#### **Thermal Characteristics**

Symbol	Parameter	Тур.	Max.	Unit
Reja	Thermal Resistance Junction to ambient		400	°C/W



## Electrical Characteristics (T $_{\rm J}$ =25 $_{\rm ^{\circ}C}$ , unless otherwise noted)

#### Off Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BVDSS	Drain- Source Breakdown Voltage	$V_{GS}$ =0 $V$ , $I_D$ =-250 $u$ A	/ <sub>GS</sub> =0V , I <sub>D</sub> =-250uA -20 .			V
BV <sub>DSS</sub> T <sub>J</sub>	BV <sub>DSS</sub> Temperature Coefficient	Reference to 25℃, I <sub>D</sub> =-1mA		-0.01		V/°C
	Drain- Source Leakage Current	$V_{DS}$ =-20 $V$ , $V_{GS}$ =0 $V$ , $T_{J}$ =25			- 1	uд
loss	Drain- Source Leakage Current	$V_{DS}$ =-16V , $V_{GS}$ =0V , $T_J$ =125			- 10	uд
Igss	Gate- Source Leakage Current	V <sub>G</sub> S 12V , V <sub>D</sub> S=0V			100	nΑ

#### On Characteristics

RDS(ON) Static Drain Source On Designance		V <sub>GS</sub> =-4.5V , I <sub>D</sub> =-1A		90	110	
Static Drain-Source On-Resistance	Static Drain-Source On-Resistance	V <sub>GS</sub> =-2.5V , I <sub>D</sub> =-1A		1 10	135	mΩ
V <sub>GS(th)</sub>	Gate Threshold Voltage	-V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =-250uA	-0.3	-0.6	- 1.0	V
V <sub>GS(th)</sub>	V <sub>GS(th)</sub> Temperature Coefficient	VGS-VDS , ID250UA		3		mV/℃
gfs	Forward Transconductance	V <sub>DS</sub> =-10V , I <sub>S</sub> =-1A		2.2		S

### Dynamic and switching Characteristics

Qg	Total Gate Charge <sup>2, 3</sup>		 4.8	8	
Qgs	Gate-Source Charge <sup>2, 3</sup>	$V_{DS}$ =-10V , $V_{GS}$ =-4.5V , $I_{D}$ =-1A	 0.5	1	nC
$Q_{gd}$	Gate-Drain Charge <sup>2, 3</sup>		 1.9	4	
T <sub>d(on)</sub>	Turn-On Delay Time <sup>2, 3</sup>		 3.5	7	
Tr	Rise Time <sup>2, 3</sup>	$V_{DD}$ =-10V , $V_{GS}$ =-4.5V , $R_{G}$ =25 $\Omega$	 12.6	24	ns
T <sub>d(off)</sub>	Turn-Off Delay Time <sup>2, 3</sup>	I <sub>D</sub> =-1A	 32.6	62	115
Tf	Fall Time <sup>2, 3</sup>		 8.4	16	
Ciss	Input Capacitance		 350	510	
Coss	Output Capacitance	$V_{DS}$ =-15V , $V_{GS}$ =0V , F=1MHz	 65	95	ΡF
Crss	Reverse Transfer Capacitance		 50	75	

#### Drain- Source Diode Characteristics and Maximum Ratings

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
ls	Continuous Source Current	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			- 1.5	Α
Ism	Pulsed Source Current	vg-vb-ov, roice current			-3	Α
VsD	Diode Forward Voltage	V <sub>GS</sub> =0V , I <sub>S</sub> =-1A , T <sub>J</sub> =25℃			- 1	V

#### Note:

- 1. Repetitive Rating: Pulsed width limited by maximum junction temperature.
- 2. The data tested by pulsed , pulse width  $\leq 300\,\text{us}$  , duty cycle  $\leq 2\,\%$  .
- ${\tt 3.} \qquad {\tt Essentially independent of operating temperature}.$

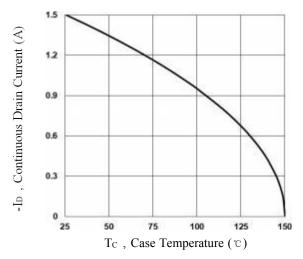


Fig. 1 Continuous Drain Current vs. T<sub>C</sub>

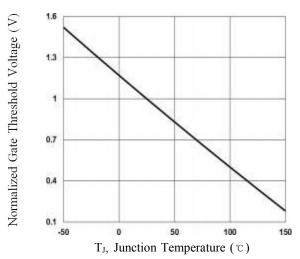


Fig. 3 Normalized V<sub>th</sub> vs. T<sub>J</sub>

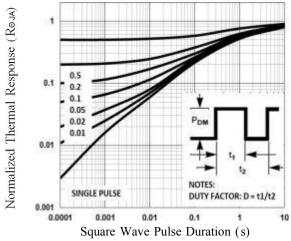


Fig. 5 Normalized Transient Response

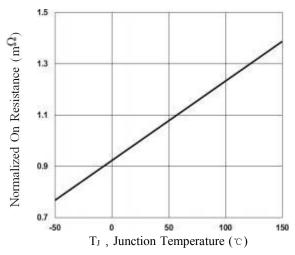


Fig. 2 Normalized RDSON vs. T<sub>J</sub>

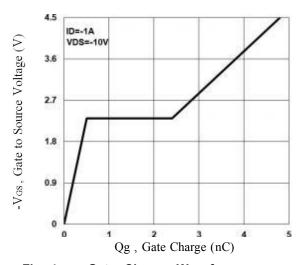


Fig. 4 Gate Charge Waveform

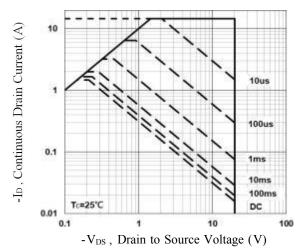
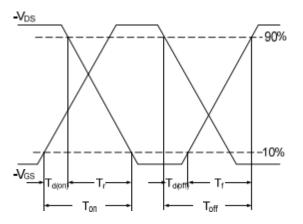


Fig. 6 Maximum Safe Operation Area







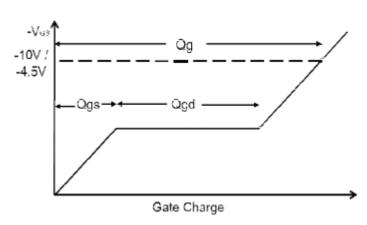
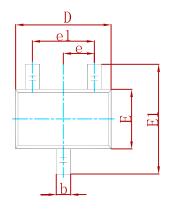
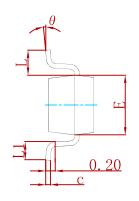


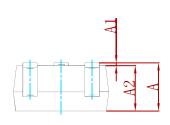
Fig. 8 Gate Charge Waveform



## **PACKAGE MECHANICAL DATA**

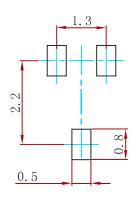






Symbol Dimensions In		In Millimeters	Dimensions	In Inches
Symbol	Min	Max	Min	Max
Α	0.900	1.100	0.035	0.043
A1	0.000	0.100	0.000	0.004
A2	0.900	1.000	0.035	0.039
b	0.200	0.400	0.008	0.016
С	0.080	0.150	0.003	0.006
D	2.000	2.200	0.079	0.087
Е	1.150	1.350	0.045	0.053
E1	2.150	2.450	0.085	0.096
е	0.650 TYP		0.026	3 TYP
e1	1.200	1.400	0.047	0.055
L	0.525 REF		0.021	I REF
L1	0.260	0.460	0.010	0.018
9	0°	8°	0°	8°

## Suggested Pad Layout



#### Note:

- 1. Controlling dimension: in millimeters.
- 2.General tolerance:±0.05mm.
- 3. The pad layout is for reference purposes only.

#### **REEL SPECIFICATION**

P/N	PKG	QTY
NTS2101PT1G-MS	SOT-323	3000



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